

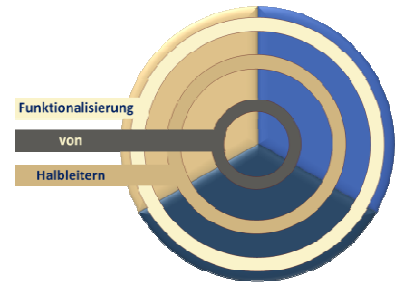
GRK 1782 „Funktionalisierung von Halbleitern – Functionalization of Semiconductors“

Workshop

„X-ray and electron beams for materials characterization“

Philipps-Universität Marburg, Fachbereich Physik, Renthof 7 HS

25. & 26. November 2013



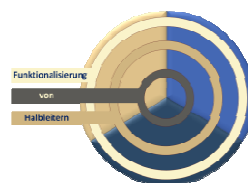
25. November 2013

- 9.00 – 10.00 Dr. Laref Slimane, FB Chemie, Philipps-Universität Marburg
Characterization of graphene-fullerene interactions: Insight from density functional theory
- 10.00 – 11.00 Dr. Miroslava Schaffer, Max Planck Institut für Biochemie, Martinsried
Advanced FIB sample preparation for TEM/STEM investigations
- 11.00 – 11.30 **coffee**
- 11.30 – 12.30 Dr. Ingo Salzmänn, Department of Physics - Humboldt-Universität zu Berlin
Thin-Film Structure Solution by X-ray Diffraction Techniques - Fundamentals
- 12.30 – 13.45 **lunch**
- 13.45 – 14.30 Dr. Miroslava Schaffer, Max Planck Institut für Biochemie, Martinsried
Cryo-Focused Ion Beam Sample Preparation of Eukaryotic Cells
- 14.30 – 15.30 Dr. Thomas Schmidt, Fritz Haber Institut der MPG, Berlin
LEEM/PEEM basics
- 15.30 – 16.00 **coffee**
- 16.00 – 17.00 Dr. Ingo Salzmänn, Department of Physics - Humboldt-Universität zu Berlin
Thin-Film Structure Solution by X-ray Diffraction Techniques - Current
- 17.00 – 18.00 Dr. Thomas Schmidt, Fritz Haber Institut der MPG, Berlin
LEEM/PEEM studies on thin film growth

Get Together

26. November 2013

- 9.00 – 10.00 Dr. Christian Kübel, Institut für Nanotechnologie, KIT, Karlsruhe
Introduction to Electron Tomography
- 10.00 – 11.00 Dr. Giuseppe Mercurio, Center for free electron laser science, Universität Hamburg
Principles of the x-ray standing wave technique
- 11.00 – 11.30 **coffee**
- 11.30 – 12.30 Dr. Lewys Jones, Dept. of Materials, University of Oxford, UK
The origins, identification and correction of scan noise in the Scanning Transmission Electron Microscopy (STEM)
- 12.30 – 13.30 **lunch**
- 13.30 – 14.30 Dr. Christian Kübel, Institut für Nanotechnologie, KIT, Karlsruhe
Advances in Electron Tomography towards a Quantitative Analysis Technique
- 14.30 – 15.30 Dr. Lewys Jones, Dept. of Materials, University of Oxford, UK
Truly quantitative HAADF STEM at atomic resolution: calculating absolute scattering cross-sections
- 15.30 – 16.00 **coffee**
- 16.00 – 17.00 Dr. Giuseppe Mercurio, Center for free electron laser science, Universität Hamburg
Unfolding molecular structures and molecule-metal interactions using x-ray standing waves



gez.: Prof. Dr. Kerstin Volz